

**Notice of References Cited**

Application/Control No.

10/634,102

Applicant(s)/Patent Under  
Reexamination  
NAKAGAWA ET AL.

Examiner

CHRISTOPHER FINDLEY

Art Unit

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0044757 A1	04-2002	KAWAMURA et al.	386/46
*	B	US-2002/0110366 A1	08-2002	Cho, Jae Ryong	386/96
*	C	US-2002/0131761 A1	09-2002	Kawasaki et al.	386/65
*	D	US-2002/0126992 A1	09-2002	Sakuramoto, Yukari	386/77
*	E	US-2003/0077071 A1	04-2003	Lin et al.	386/68
*	F	US-6,959,141 B1	10-2005	Ichikawa et al.	386/95
*	G	US-7,095,951 B2	08-2006	Moriyama et al.	386/95
*	H	US-7,106,946 B1	09-2006	Kato, Motoki	386/69
*	I	US-7,178,106 B2	02-2007	Lamkin et al.	715/716
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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